

Process C3015

CMOS 3 μ m

Digital

Electrical Characteristics

T=25°C Unless otherwise noted

N-Channel Transistor	Symbol	Minimum	Typical	Maximum	Unit	Comments
Threshold Voltage	V_{T_N}	0.6	0.8	1.0	V	100x3 μ m
Body Factor	γ_N		0.6		V ^{1/2}	100x3 μ m
Conduction Factor	β_N	42	47	52	μ A/V ²	100x100 μ m
Effective Channel Length	L_{eff_N}	2.85	3.2	3.55	μ m	100x3 μ m
Width Encroachment	ΔW_N		0.7		μ m	Per side
Punch Through Voltage	$BVDSS_N$	12			V	
Poly Field Threshold Voltage	$VTF_{P(N)}$	12			V	

P-Channel Transistor	Symbol	Minimum	Typical	Maximum	Unit	Comments
Threshold Voltage	V_{T_P}	-0.6	-0.8	-1.0	V	100x3 μ m
Body Factor	γ_P		0.55		V ^{1/2}	100x3 μ m
Conduction Factor	β_P	13	15	19	μ A/V ²	100x100 μ m
Effective Channel Length	L_{eff_P}	2.85	3.2	3.55	μ m	100x3 μ m
Width Encroachment	ΔW_P		0.9		μ m	Per side
Punch Through Voltage	$BVDSS_P$	-12			V	
Poly Field Threshold Voltage	$VTF_{P(P)}$	-12			V	

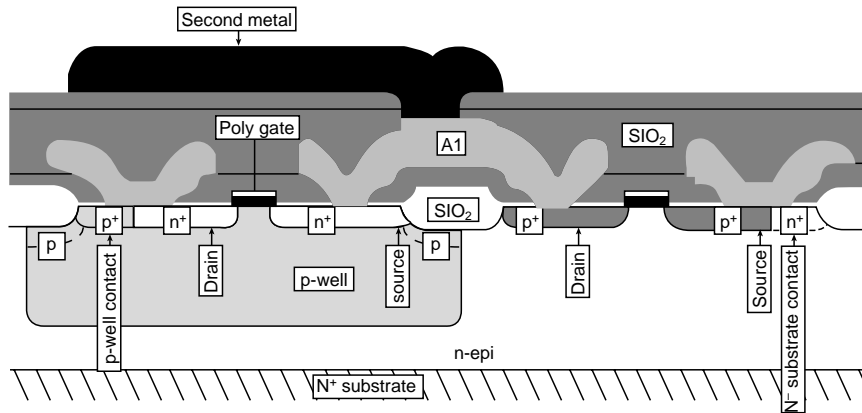
Diffusion & Thin Films	Symbol	Minimum	Typical	Maximum	Unit	Comments
Well (field) Sheet Resistance	$\rho_{P-well(f)}$	3.2	4.8	6.5	K Ω / \square	P-well
N+ Sheet Resistance	ρ_{N+}	16	21	27	Ω / \square	
N+ Junction Depth	X_{jN+}		0.8		μ m	
P+ Sheet Resistance	ρ_{P+}	50	80	100	Ω / \square	
P+ Junction Depth	X_{jP+}		0.7		μ m	
Gate Oxide Thickness	T_{GOX}	37.5	40.0	42.5	nm	
Gate Poly Sheet Resistance	ρ_{POLY1}	15	22	30	Ω / \square	
Metal-1 Sheet Resistance	ρ_{M1}		30	60	m Ω / \square	
Passivation Thickness	T_{PASS}		200+900		nm	oxide+nit.

Capacitance	Symbol	Minimum	Typical	Maximum	Unit	Comments
Gate Oxide	C_{OX}	0.66	0.72	0.78	fF/ μ m ²	
Metal-1 to Poly-1	C_{M1P}		0.0523		fF/ μ m ²	
Metal-1 to Silicon	C_{M1S}	0.026	0.030	0.034	fF/ μ m ²	

Physical Characteristics

Starting Material	N <100>	N+/P+ Width/Space	3.0 / 3.0 μ m
Starting Mat. Resistivity	15 - 25 Ω -cm	N+ To P+ Space	12 μ m
Typ. Operating Voltage	5V	Contact To Poly Space	2.5 μ m
Well Type	P-well	Contact Overlap Of Diffusion	1.5 μ m
Metal Layers	1	Contact Overlap Of Poly	1.0 μ m
Poly Layers	1	Metal-1 Overlap Of Contact	1.0 μ m
Contact Size	2.0x2.0 μ m	Minimum Pad Opening	100x100 μ m
Metal-1 Width/Space	3.5 / 2.5 μ m	Minimum Pad-to-Pad Spacing	5.0 μ m
Gate Poly Width/Space	3.0 / 2.5 μ m	Minimum Pad Pitch	80.0 μ m

Special Feature of C3015 Process: 3 μ m P-well digital process.



Cross-sectional view of the C3015 process

